

# HIGH-SPEED CMOS OCTAL BUFFER/LINE DRIVER

IDT54/74AHCT240

#### **FEATURES:**

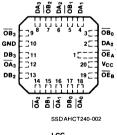
- Equivalent to ALS speeds and output drive over full temperature and voltage supply extremes
- · 7ns typical data to output delay
- IOI = 14mA over full military temperature range
- CMOS power levels (5μW typ. static)
- Both CMOS and TTL output compatible
- Substantially lower input current levels than ALS (5μA max.)
- · Octal buffer/line driver with 3-state output
- 100% product assurance screening to MIL-STD-883, Class B is available
- · JEDEC standard pinout for DIP and LCC

#### **DESCRIPTION:**

The IDT54/74AHCT240 is an octal buffer/line driver built using advanced CEMOS™, a dual metal CMOS technology. The device is designed to be employed as a memory and address driver, clock driver and bus-oriented transmitter/receiver which provides improved board density.

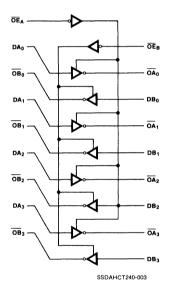
#### PIN CONFIGURATION

#### □ Vcc T OEB DAo OA<sub>0</sub> OBo DB<sub>0</sub> DA T ОВ₁Г OA1 DA<sub>2</sub> DB<sub>1</sub> OA<sub>2</sub> ŌB₂ [ DA<sub>3</sub> DB<sub>2</sub> OB<sub>3</sub> OA<sub>3</sub> GND DB<sub>3</sub> SSDAHCT240-001 DIP TOP VIEW



LCC TOP VIEW

#### **FUNCTIONAL BLOCK DIAGRAM**



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## **ABSOLUTE MAXIMUM RATING(1)**

SYMBOL RATING		COMMERCIAL	MILITARY	UNIT	
V <sub>TERM</sub>	Terminal Voltage with Respect to GND	-0.5 to +7.0	-0.5 to +7.0	٧	
T <sub>A</sub>	Operating Temperature	0 to +70	-55 to +125	°C	
T <sub>BIAS</sub>	Temperature Under Bias	-55 to +125	-65 to +135	°C	
T <sub>STG</sub>	Storage Temperature	-55 to +125	-65 to +155	°C	
I <sub>OUT</sub>	DC Output Current	120	120	mA	

### DC ELECTRICAL CHARACTERISTICS OVER OPERATING RANGE

Following Conditions Apply Unless Otherwise Specified:

 $T_A = 0^{\circ}C$  to +70°C

 $V_{CC} = 5.0V \pm 5\%$ 

 $V_{CC} = 5.0V \pm 10\%$ 

Min. = 4.75V Min. = 4.50V Max. = 5.25V (Commercial)

Max. = 5.50V (Military)

 $V_{LC} = 0.2V$  $V_{HC} = V_{CC} - 0.2V$ 

 $T_A = -55^{\circ}C \text{ to } +125^{\circ}C$ 

SYMBOL	PARAMETER	TEST CO	TEST CONDITIONS(1)			MAX.	UNIT
V <sub>IH</sub>	Input HIGH Level	Guaranteed Logic	Guaranteed Logic High Level				V
V <sub>IL</sub>	Input LOW Level	Guaranteed Logic	Low Level	_	-	0.8	V
I <sub>IH</sub>	Input HIGH Current	V <sub>CC</sub> = Max., V <sub>IN</sub> = V	cc	l –	_	5	μΑ
I <sub>IL</sub>	Input LOW Current	V <sub>CC</sub> = Max., V <sub>IN</sub> = C	V <sub>CC</sub> = Max., V <sub>IN</sub> = GND		_	-5	μА
I <sub>sc</sub>	Short Circuit Current	V <sub>CC</sub> = Max. (3)	V <sub>CC</sub> = Max. <sup>(3)</sup>			_	mA
	Output HIGH Voltage	V <sub>CC</sub> = 3V, V <sub>IN</sub> = V <sub>LC</sub>	$V_{CC} = 3V$ , $V_{IN} = V_{LC}$ or $V_{HC}$ , $I_{OH} = -32\mu A$		V <sub>CC</sub>	_	
V			I <sub>OH</sub> = -150μA	V <sub>HC</sub>	V <sub>CC</sub>	_	V
$V_{OH}$		V <sub>CC</sub> = Min. V <sub>IN</sub> = V <sub>IH</sub> or V <sub>II</sub>	I <sub>OH</sub> = -12mA MIL	2.4	4.3	_	
		VIN - VIH OF VIL	I <sub>OH</sub> = -15mA COM	2.4	4.3	_	
	Output LOW Voltage	V <sub>CC</sub> = 3V, V <sub>IN</sub> = V <sub>LC</sub>	$V_{CC} = 3V$ , $V_{IN} = V_{LC}$ or $V_{HC}$ , $I_{OL} = 300 \mu A$		GND	V <sub>LC</sub>	
M			I <sub>OL</sub> = 300μA	_	GND	V <sub>LC</sub>	v
$V_{OL}$		V <sub>CC</sub> = Min. V <sub>IN</sub> = V <sub>IH</sub> or V <sub>II</sub>	I <sub>OL</sub> = 14mA MIL	_	_	0.4	"
		VIN - VIH OF VIL	I <sub>OL</sub> = 24mA COM	-		0.5	

<sup>1.</sup>Stresses greater than those listed under ABSOLUTE MAXIMUM RATINGS may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.

<sup>1.</sup> For conditions shown as max, or min., use appropriate value specified under Electrical Characteristics for the applicable device type.

<sup>2.</sup> Typical values are at  $V_{CC}$  = 5.0V, +25°C ambient and maximum loading.

<sup>3.</sup> Not more than one output should be shorted at one time. Duration of the short circuit test should not exceed one second.

#### **POWER SUPPLY CHARACTERISTICS**

 $V_{LC} = 0.2V$ ;  $V_{HC} = V_{CC} - 0.2V$ 

SYMBOL	PARAMETER	$ \begin{array}{c} \textbf{TEST CONDITIONS}^{(1)} \\ V_{CC} = Max. \\ V_{IN} \geq V_{HC}; \ V_{IN} \leq V_{LC} \\ f_i = 0 \end{array} $		MIN.	TYP.(2)	MAX.	UNIT
Icca	Quiescent Power Supply Current			_	0.001	1.5	mA
I <sub>CCT</sub>	Power Supply Current TTL Inputs HIGH	V <sub>CC</sub> = Max, V <sub>IN</sub> = 3.4V <sup>(3)</sup>			0.5	1.6	mA
I <sub>CCD</sub>	Dynamic Power Supply Current	V <sub>CC</sub> = Max. Outputs Open OE <sub>A</sub> = OE <sub>B</sub> = GND One Input Toggling 50% Duty Cycle	$\begin{aligned} & V_{IN} \geq V_{HC}; \\ & V_{IN} \leq V_{LC} \end{aligned}$	_	0.15	0.25	mA/ MHz
I <sub>CC</sub> Total Power Supply Current		V <sub>CC</sub> = Max. Outputs Open f <sub>i</sub> = 1.0MHz	$\begin{aligned} &V_{\text{IN}} \geq V_{\text{HC}}; \\ &V_{\text{IN}} \leq V_{\text{LC}} \left( \text{AHCT} \right) \end{aligned}$	_	0.15	1.8	mA
	Total Power Supply <sup>(4)</sup>	$\frac{50\%}{OE_A}$ Duty Cycle $OE_A = OE_B = GND$ One Bit Toggling	V <sub>IN</sub> = 3.4V or V <sub>IN</sub> = GND	_	0.4	2.6	
	Current	V <sub>CC</sub> = Max. Outputs Open f <sub>i</sub> = 250KHz	$\begin{aligned} &V_{IN} \geq V_{HC}; \\ &V_{IN} \leq V_{LC}  (AHCT) \end{aligned}$		0.3	2.0	
		$\frac{50\%}{OE_A}$ Duty Cycle $OE_A = OE_B = GND$ Eight Bits Toggling	V <sub>IN</sub> = 3.4V or V <sub>IN</sub> = GND	_	2.3	8.4	

#### NOTES

- 1. For conditions shown as max. or min., use appropriate value specified under Electrical Characteristics for the applicable device type.
- 2. Typical values are at V<sub>CC</sub> = 5.0V, +25°C ambient and maximum loading.
- 3. Per TTL driven input ( $V_{IN}$  = 3.4V); all other inputs at  $V_{CC}$  or GND.
- 4. ICC = IQUIESCENT + IINPUTS + IDYNAMIC
  - $I_{\text{CC}} = I_{\text{CCQ}} + I_{\text{CCT}} D_{\text{H}} N_{\text{T}} + I_{\text{CCD}} \left(f_{\text{CP}}/2 + f_{\text{i}} N_{\text{i}}\right)$
- I<sub>CCQ</sub> = Quiescent Current
- $I_{CCT}$  = Power Supply Current for a TTL High Input ( $V_{IN}$  = 3.4V)
- D<sub>H</sub> = Duty Cycle for TTL Inputs High
- N<sub>T</sub> = Number of TTL Inputs at D<sub>H</sub>
- I<sub>CCD</sub> = Dynamic Current caused by an Input Transition pair (HLH or LHL)
- f<sub>CP</sub> = Clock Frequency for Register Devices (Zero for Non-Register Devices)
  - f<sub>i</sub> = Input Frequency
- N<sub>j</sub> = Number of Inputs at f<sub>j</sub>

All currents are in milliamps and all frequencies are in megahertz.

# **DEFINITION OF FUNCTIONAL TERMS**

PIN NAMES	DESCRIPTION				
OE <sub>A</sub> , OE <sub>B</sub>	3-State Output Enable Input (Active LOW)				
<u>D</u> xx	Inputs				
l Oxx	Outputs				

# TRUTH TABLE

INPUTS	OUTPUT			
OE <sub>A</sub> , OE <sub>B</sub>	D	001701		
L	L	Н		
L	Н	L		
Н	Х	z		

H = HIGH Voltage Level L = LOW Voltage Level X = Don't Care Z = High Impedance

# **SWITCHING CHARACTERISTICS OVER OPERATING RANGE**

SYMBOL	0.0.44		=======================================	COMMERCIAL		MILITARY		UNITS
	PARAMETER	CONDITION	TYPICAL	MIN.	MAX.	MIN.	MAX.	UNITS
t <sub>PLH</sub> t <sub>PHL</sub>	Propagation Delay D <sub>N</sub> to O <sub>N</sub>	C <sub>L</sub> = 50pf R <sub>L</sub> = 500Ω	7.0	2.0	9.0	2.0	12.0	ns
t <sub>ZH</sub> t <sub>ZL</sub>	Output Enable Time		15.0	5.0	18.0	5.0	20.0	ns
t <sub>HZ</sub> t <sub>LZ</sub>	Output Disable Time		10.0	2.0	12.0	2.0	18.0	ns